

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	((("6062225") or ("6331659")).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:42
L2	626	(600/310).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:42
L3	3335	(128/922,898).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L4	395	(250/363.02).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L5	1530	(435/2).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L6	399	(800/14,24).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:43
L7	280	(377/10).CCLS.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/22 14:44
L8	6544	2 or 3 or 4 or 5 or 6 or 7	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
L9	269	8 and retard\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
L10	9	8 and (retard\$4 same imag\$4)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 14:44
S1	0	retard\$4 near3 "3nm"	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/22 11:50
S2	0	retard\$4 same "3nm"	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:55
S3	200	retard\$4 same imag\$4 same intensity	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:56
S4	5	S3 and spindle	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:58
S5	88	meiotic near2 spindle	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:59

S6	0	S5 and retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 11:59
S7	17	S5 and retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 12:01
S8	160125	retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 12:01
S9	3713	retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 13:03
S10	19	oocyte same retard\$5	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:14
S11	0	meiotic same spindle same oocyte same structure same retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:15
S12	0	meiotic same spindle same oocyte same structure same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:15
S13	0	meiotic same oocyte same structure same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:16
S14	1	meiotic same oocyte same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:17
S15	2	((("6062255") or ("6331659"))).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/19 14:19
S16	2	((("6062225") or ("6331659"))).PN.	US-PGPUB; USPAT; IBM_TDB	OR	OFF	2004/11/19 14:19
S17	30	("2022164"   "2495878"   "2623367"   "2809800"   "3254504"   "3456803"   "3608579"   "3982406"   "4207994"   "4436109"   "4577657"   "4599166"   "4776952"   "4792059"   "4946599"   "5003790"   "5045197"   "5064097"   "5083442"   "5244009"   "5269442"   "5285815"   "5336406"   "5607083").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/11/19 14:20
S18	0	spindle same retardance same image	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:22
S19	1	spindle same retardance same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:26

S20	0	retardance same sensitiv\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:26
S21	55	retardance same sensitiv\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:34
S22	0	S21 and meiotic	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:27
S23	1	spindle same retardance	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:37
S24	7	spindle same meiotic same mammalian same oocyte	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:40
S25	2	S24 and retard\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:38
S26	2093	spindle same imag\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:40
S27	0	S26 same retardacne	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41
S28	0	S26 and retardacne	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41
S29	22	S26 and retarda\$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/11/19 14:41

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retardan\* &lt;paragraph&gt; imag\*

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Tyo, J.S.;

Antennas and Propagation Society International Symposium, 2000. IEEE , Vol 2 , 16-21 July 2000

Pages:670 - 673 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(172 KB\)\]](#)   IEEE CNF

**2 Imaging polarimetry with an micro-retarder array**

Kikuta, H.; Numata, K.; Arimitsu, H.; Iwata, K.; Kato, N.;

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 4 , 5-7 2002

Pages:2510 - 2511 vol.4

[\[Abstract\]](#)   [\[PDF Full-Text \(246 KB\)\]](#)   IEEE CNF

**3 Analysis of Mueller matrix images by polar decomposition**

Chung, J.R.; Cote, G.L.; DeLaughter, A.H.; Baba, J.S.;

[Engineering in Medicine and Biology, 2002. 24th Annual Conference and the Annual Fall Meeting of the Biomedical Engineering Society] EMBS/BMES

Conference, 2002. Proceedings of the Second Joint , Volume: 3 , 23-26 Oct. 2 Pages:2308 - 2309 vol.3

[\[Abstract\]](#)   [\[PDF Full-Text \(369 KB\)\]](#)   IEEE CNF

**4 A new generation tree retardant insulation compound for medium**

**voltage power cable***Lorigan, P.;*

Rural Electric Power Conference, 1999 , 2-4 May 1999

Pages:D2/1 - D210

[\[Abstract\]](#)   [\[PDF Full-Text \(888 KB\)\]](#)   IEEE CNF**5 The development of elastomeric insulating materials for use under extreme service conditions***Warren, L.; Paterson, J.R.;*

Dielectric Materials, Measurements and Applications, 1988., Fifth International Conference on , 27-30 Jun 1988

Pages:143 - 146

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